

Search Notes

Application/Control No.

10/710,766

Examiner

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Applicant(s)/Patent under
Reexamination

NIEH ET AL.

Art Unit

2181

SEARCHED

Class	Subclass	Date	Examiner
710	5- 10,33,62- 66,72- 73,105- 106	6/20/2007	CS
365	189.1	6/20/2007	CS
365	233	6/20/2007	CS
377	75	6/20/2007	CS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
710	62, 5	6/21/2007	CS

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS	6/20/2007	CS
PALM for Double Patenting	6/20/2007	CS
EAST (USPGPUB,USPAT,USOCR,FPRS,E PO,JPO,DERWENT,IBMTDB)	6/20/2007	CS